



US00D457078S

(12) **United States Design Patent** (10) **Patent No.:** **US D457,078 S**  
**Devlin et al.** (45) **Date of Patent:** **\*\* May 14, 2002**

(54) **OFFSET PROBE THERMOMETER**

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(73) Assignee: **Chaney Instrument Company**, Lake Geneva, WI (US)

(\*\*) Term: **14 Years**

(21) Appl. No.: **29/138,888**

(22) Filed: **Mar. 21, 2001**

(51) **LOC (7) Cl.** ..... **10-04**

(52) **U.S. Cl.** ..... **D10/57**

(58) **Field of Search** ..... D10/57; D7/653, D7/683; 30/129, 142, 147, 148, 150, 322, 323; 294/55.5, 61; 374/141, 155, 184, 208-210

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

D439,809 S \* 4/2001 Ming et al. .... D10/57

\* cited by examiner

*Primary Examiner*—Antoine Duval Davis

(74) *Attorney, Agent, or Firm*—Michael Best & Friedrich, LLC

(57) **CLAIM**

The ornamental design for a offset probe thermometer, as shown.

**DESCRIPTION**

FIG. 1 is a front perspective view of the offset probe thermometer of the present invention;

FIG. 2 is a right side elevation view of the offset probe thermometer shown in FIG. 1, the left side elevation view being a mirror image thereof;

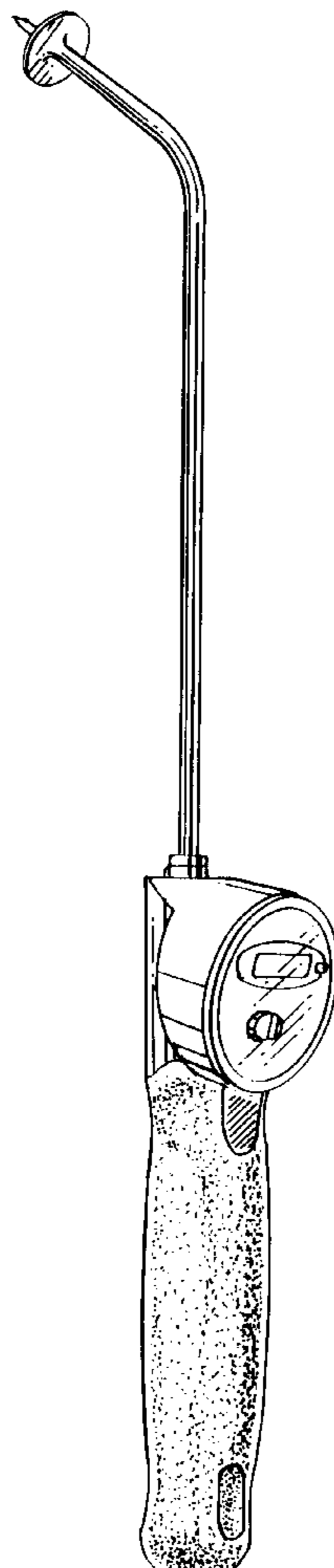
FIG. 3 is a front elevation view of the offset probe thermometer of FIG. 1;

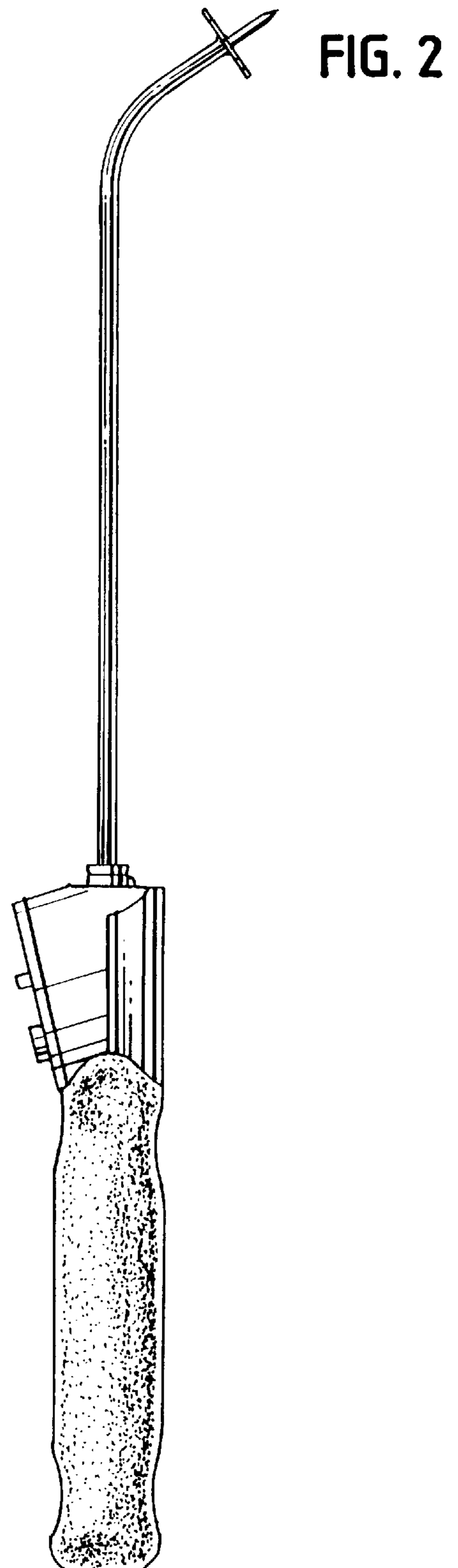
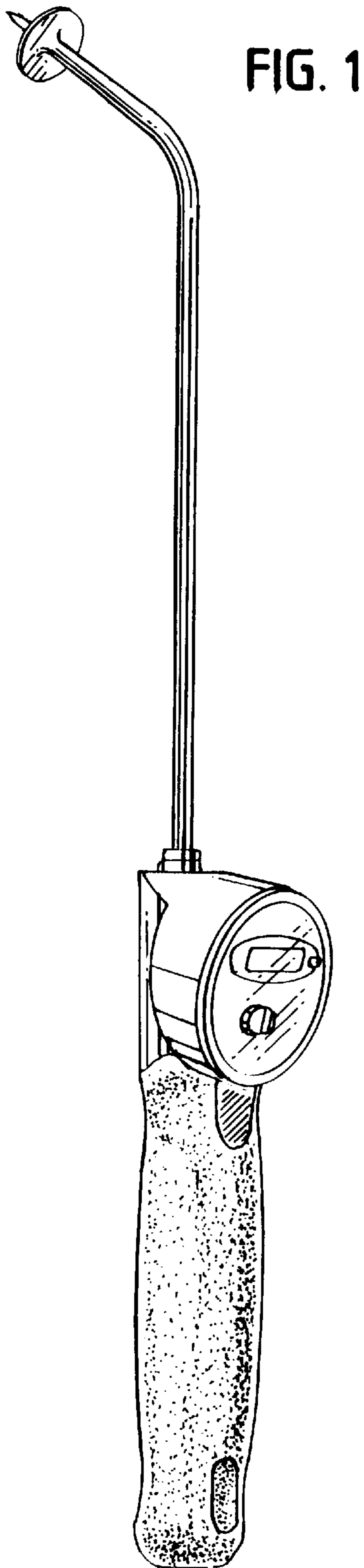
FIG. 4 is a top plan view of the offset probe thermometer shown in FIG. 1;

FIG. 5 is a bottom plan view of the offset probe thermometer shown in FIG. 1; and,

FIG. 6 is a back plan view of the offset probe thermometer shown in FIG. 2.

**1 Claim, 2 Drawing Sheets**





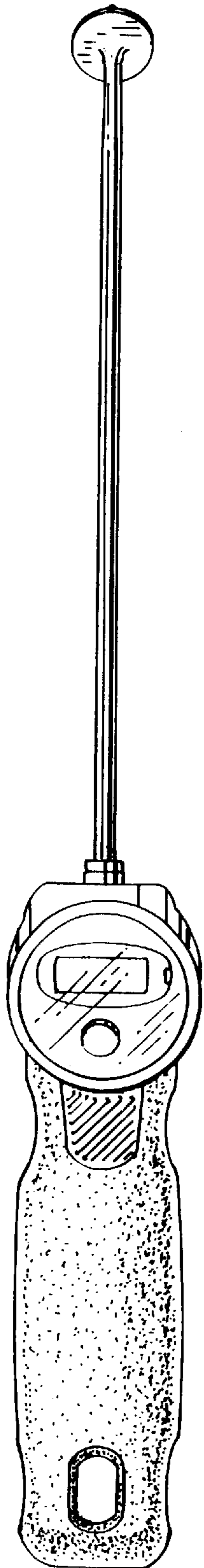


FIG. 3

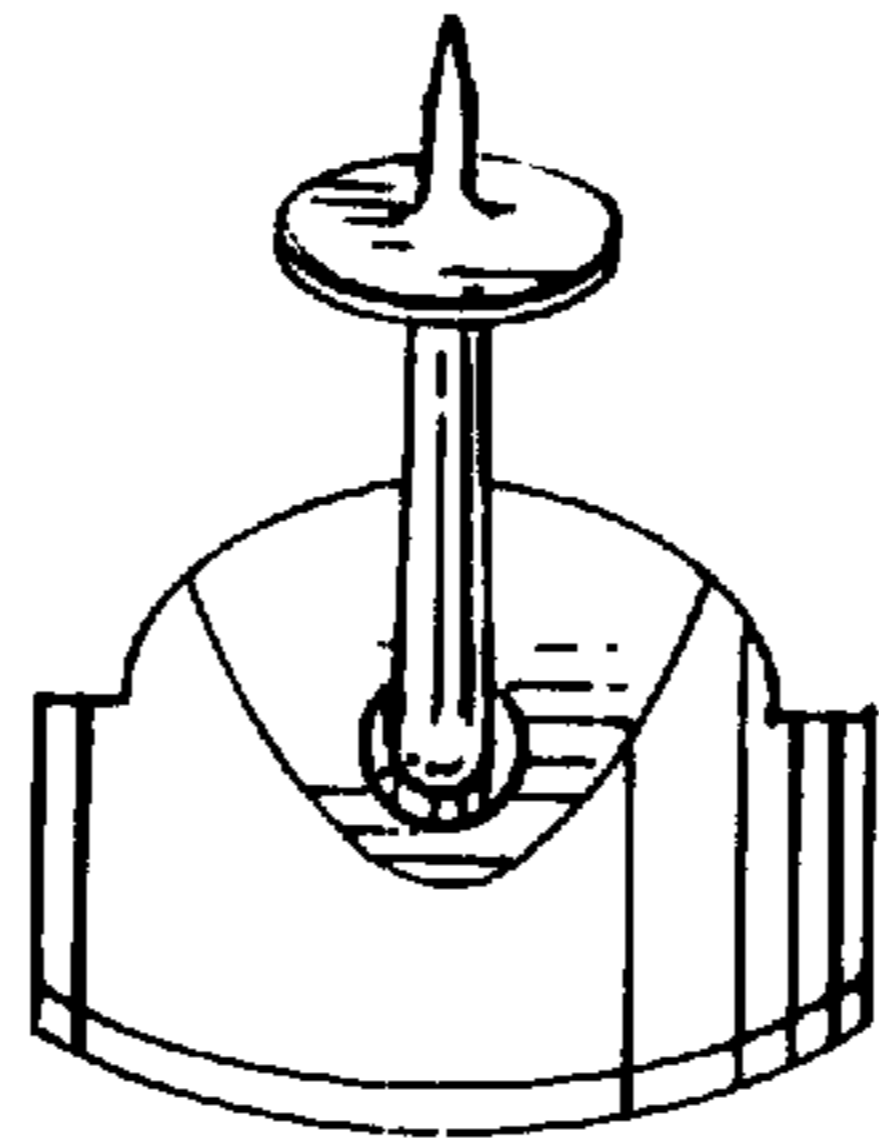


FIG. 4

FIG. 5

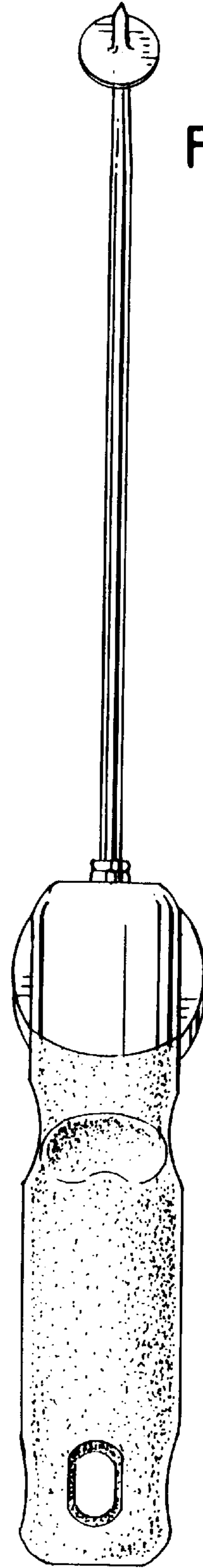
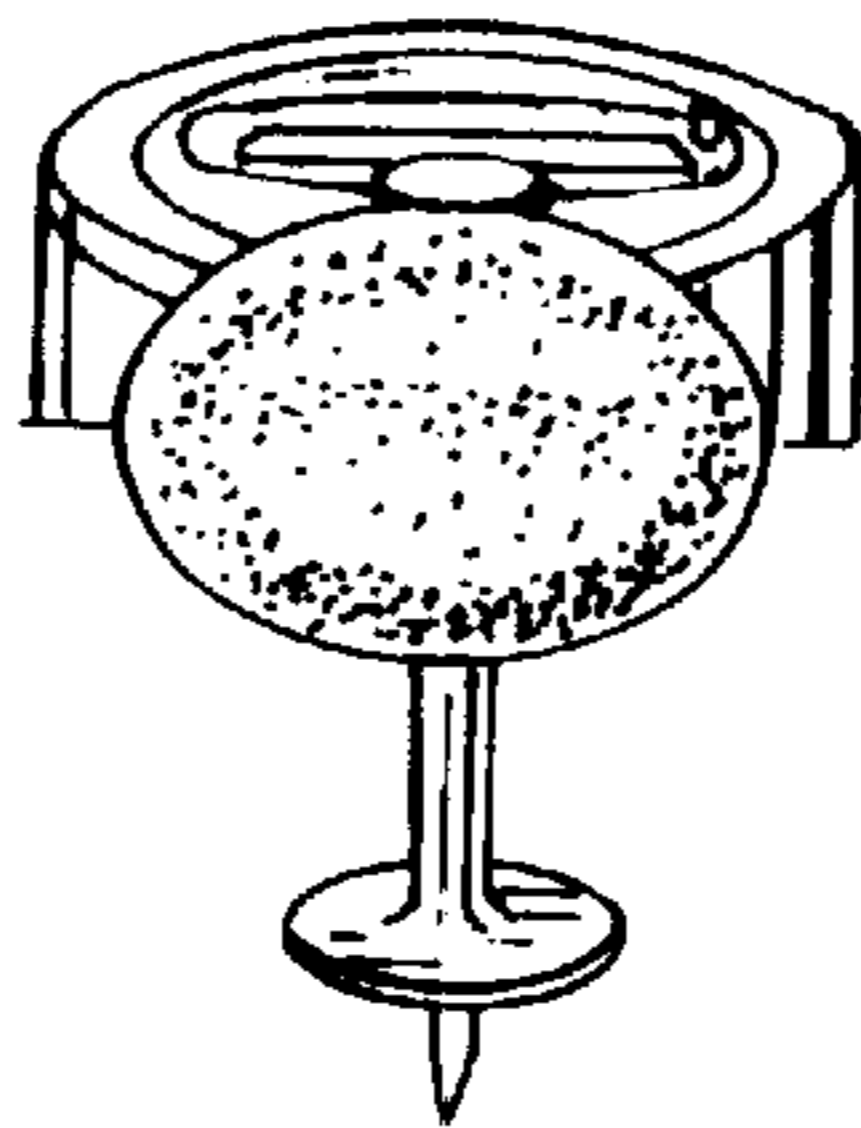


FIG. 6